

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/572,702	FUTAMI, TOSHIHIKO
	Examiner	Art Unit
	Tran N. Nguyen	2834

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
H02K 1/27 24 22	4/12/ 07	DNB
H02K 21/12 14 16		
Text search & Interferen search	4/13/ 07	DNW

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
310	<u>all above</u>	4/13/07	JNN